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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	598
Number of Logic Elements/Cells	5980
Total RAM Bits	92160
Number of I/O	185
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	240-BFQFP
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1c6q240c8n

1. Introduction

C51001-1.5

Introduction

The Cyclone® field programmable gate array family is based on a 1.5-V, 0.13-µm, all-layer copper SRAM process, with densities up to 20,060 logic elements (LEs) and up to 288 Kbits of RAM. With features like phase-locked loops (PLLs) for clocking and a dedicated double data rate (DDR) interface to meet DDR SDRAM and fast cycle RAM (FCRAM) memory requirements, Cyclone devices are a cost-effective solution for data-path applications. Cyclone devices support various I/O standards, including LVDS at data rates up to 640 megabits per second (Mbps), and 66- and 33-MHz, 64- and 32-bit peripheral component interconnect (PCI), for interfacing with and supporting ASSP and ASIC devices. Altera also offers new low-cost serial configuration devices to configure Cyclone devices.

Features

The Cyclone device family offers the following features:

- 2,910 to 20,060 LEs, see Table 1–1
- Up to 294,912 RAM bits (36,864 bytes)
- Supports configuration through low-cost serial configuration device
- Support for LVTTL, LVCMOS, SSTL-2, and SSTL-3 I/O standards
- Support for 66- and 33-MHz, 64- and 32-bit PCI standard
- High-speed (640 Mbps) LVDS I/O support
- Low-speed (311 Mbps) LVDS I/O support
- 311-Mbps RSDS I/O support
- Up to two PLLs per device provide clock multiplication and phase shifting
- Up to eight global clock lines with six clock resources available per logic array block (LAB) row
- Support for external memory, including DDR SDRAM (133 MHz), FCRAM, and single data rate (SDR) SDRAM
- Support for multiple intellectual property (IP) cores, including Altera® MegaCore® functions and Altera Megafunctions Partners Program (AMPP℠) megafunctions.

Table 1–1. Cyclone Device Features (Part 1 of 2)

Feature	EP1C3	EP1C4	EP1C6	EP1C12	EP1C20
LEs	2,910	4,000	5,980	12,060	20,060
M4K RAM blocks (128 × 36 bits)	13	17	20	52	64

Byte Enables

M4K blocks support byte writes when the write port has a data width of 16, 18, 32, or 36 bits. The byte enables allow the input data to be masked so the device can write to specific bytes. The unwritten bytes retain the previous written value. Table 2–5 summarizes the byte selection.

Table 2–5. Byte Enable for M4K Blocks Notes (1), (2)

byteena[3..0]	datain ×18	datain ×36
[0] = 1	[8..0]	[8..0]
[1] = 1	[17..9]	[17..9]
[2] = 1	—	[26..18]
[3] = 1	—	[35..27]

Notes to Table 2–5:
(1) Any combination of byte enables is possible.
(2) Byte enables can be used in the same manner with 8-bit words, i.e., in ×16 and ×32 modes.

Control Signals and M4K Interface

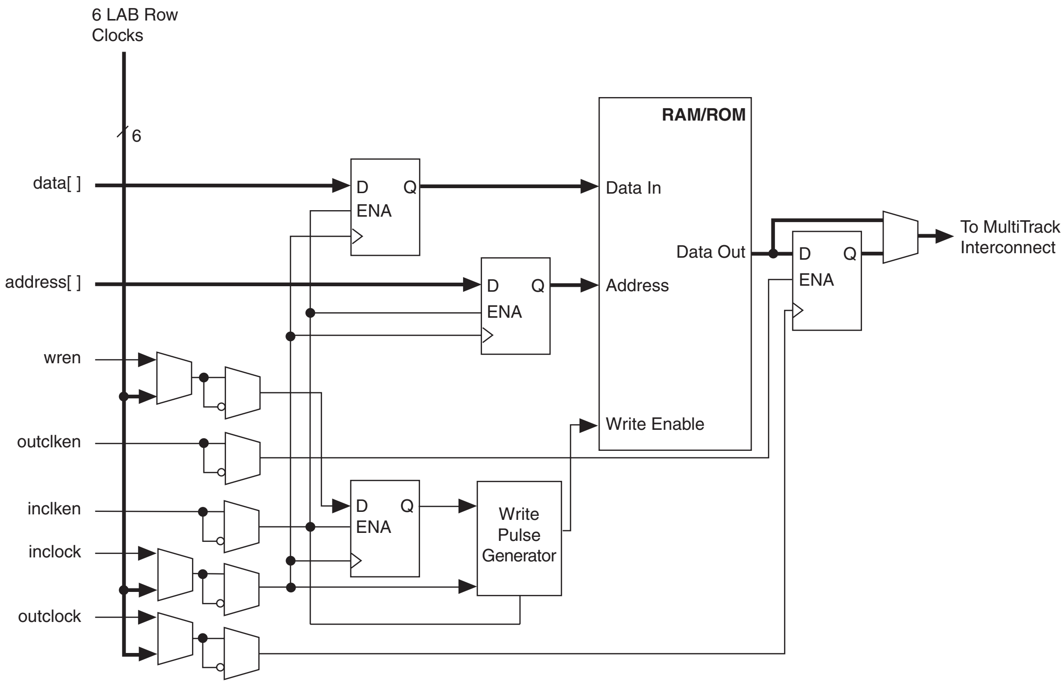
The M4K blocks allow for different clocks on their inputs and outputs. Either of the two clocks feeding the block can clock M4K block registers (`renwe`, address, byte enable, `datain`, and output registers). Only the output register can be bypassed. The six `labclk` signals or local interconnects can drive the control signals for the A and B ports of the M4K block. LEs can also control the `clock_a`, `clock_b`, `renwe_a`, `renwe_b`, `clr_a`, `clr_b`, `clocken_a`, and `clocken_b` signals, as shown in Figure 2–15.

The R4, C4, and direct link interconnects from adjacent LABs drive the M4K block local interconnect. The M4K blocks can communicate with LABs on either the left or right side through these row resources or with LAB columns on either the right or left with the column resources. Up to 10 direct link input connections to the M4K block are possible from the left adjacent LABs and another 10 possible from the right adjacent LAB. M4K block outputs can also connect to left and right LABs through 10 direct link interconnects each. Figure 2–16 shows the M4K block to logic array interface.

Single-Port Mode

The M4K memory blocks also support single-port mode, used when simultaneous reads and writes are not required. See Figure 2–21. A single M4K memory block can support up to two single-port mode RAM blocks if each RAM block is less than or equal to 2K bits in size.

Figure 2–21. Single-Port Mode *Note (1)*



Note to Figure 2–21:

(1) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

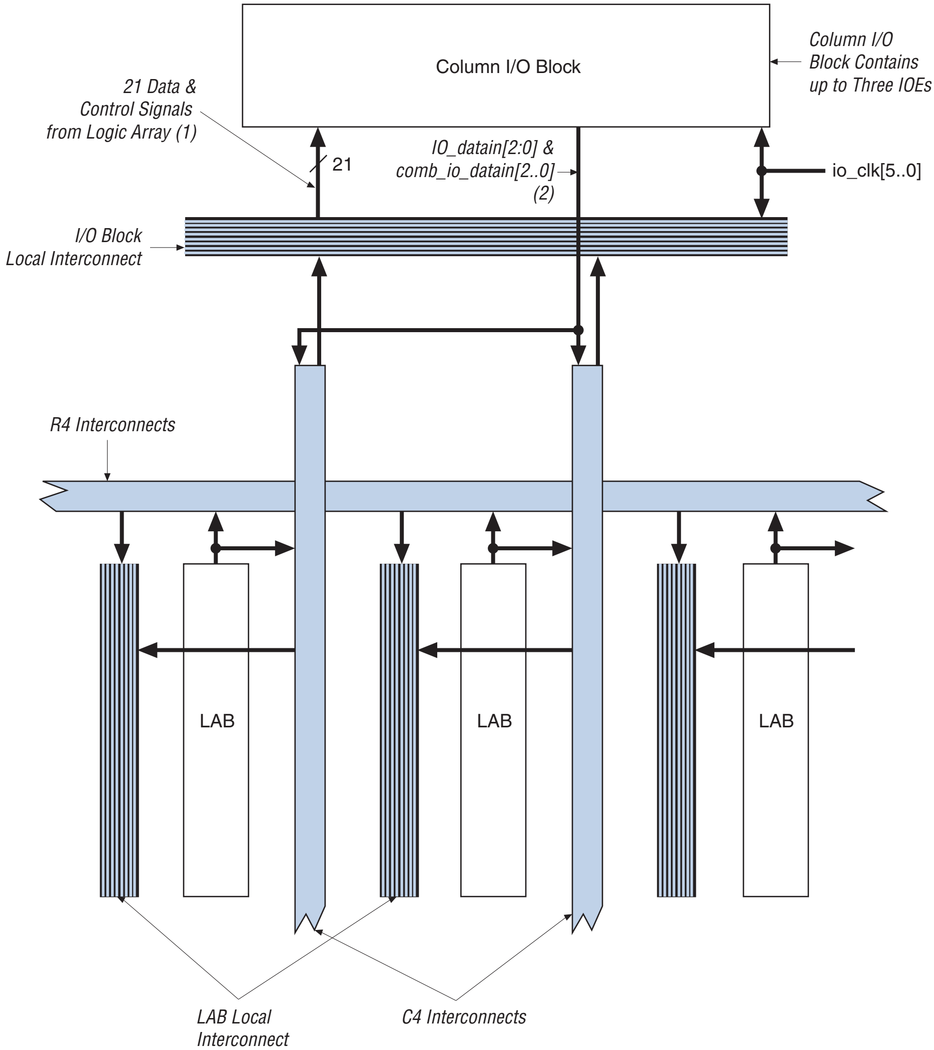
Global Clock Network and Phase-Locked Loops

Cyclone devices provide a global clock network and up to two PLLs for a complete clock management solution.

Global Clock Network

There are four dedicated clock pins (`CLK[3..0]`, two pins on the left side and two pins on the right side) that drive the global clock network, as shown in Figure 2–22. PLL outputs, logic array, and dual-purpose clock (`DPCLK[7..0]`) pins can also drive the global clock network.

Figure 2–29. Column I/O Block Connection to the Interconnect

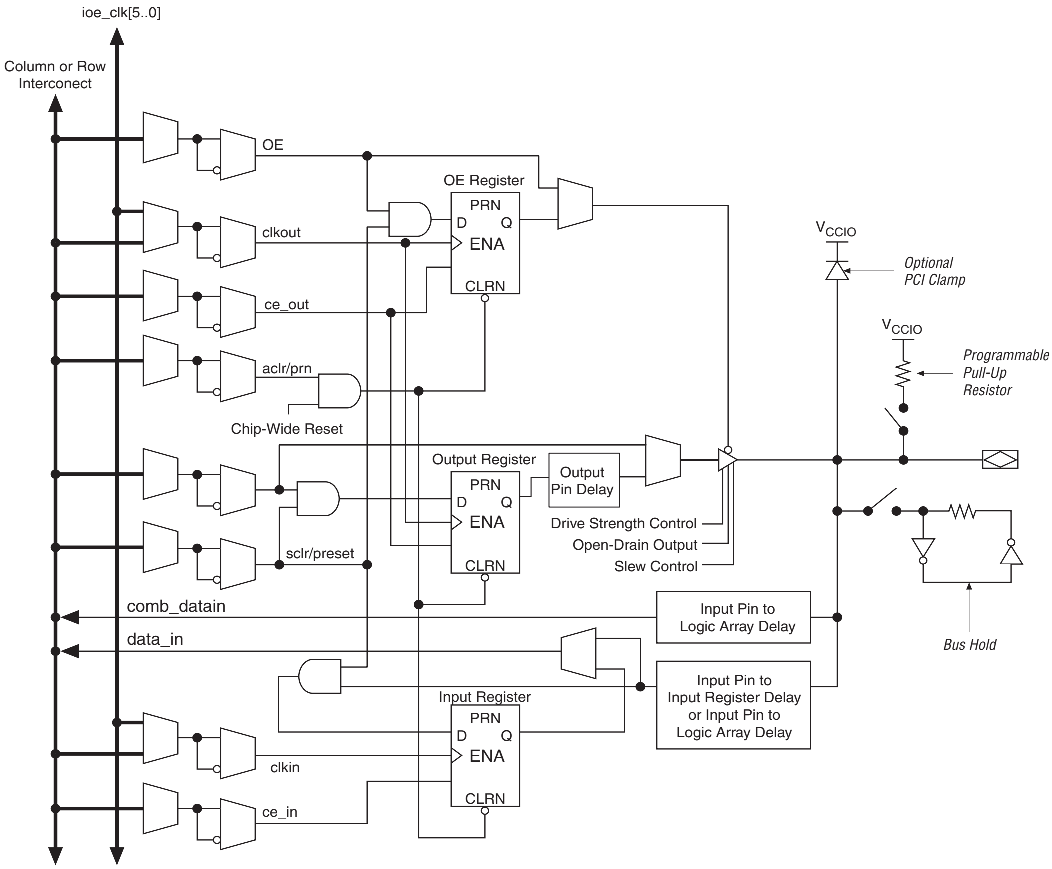


Notes to Figure 2–29:

(1) The 21 data and control signals consist of three data out lines, `io_dataout[2..0]`, three output enables, `io_coe[2..0]`, three input clock enables, `io_cce_in[2..0]`, three output clock enables, `io_cce_out[2..0]`, three clocks, `io_cclk[2..0]`, three asynchronous clear signals, `io_caclr[2..0]`, and three synchronous clear signals, `io_csclr[2..0]`.

(2) Each of the three IOEs in the column I/O block can have one `io_datain` input (combinatorial or registered) and one `comb_io_datain` (combinatorial) input.

Figure 2–32. Cyclone IOE in Bidirectional I/O Configuration

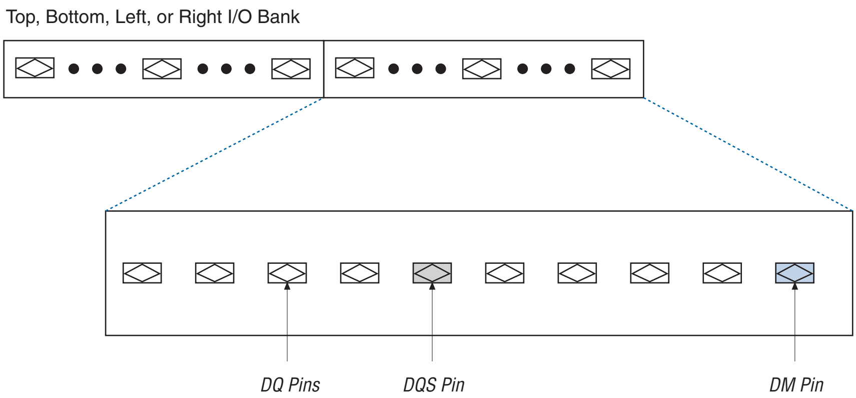


The Cyclone device IOE includes programmable delays to ensure zero hold times, minimize setup times, or increase clock to output times.

A path in which a pin directly drives a register may require a programmable delay to ensure zero hold time, whereas a path in which a pin drives a register through combinatorial logic may not require the delay. Programmable delays decrease input-pin-to-logic-array and IOE input register delays. The Quartus II Compiler can program these delays output pins (nSTATUS and CONF_DONE) and all the JTAG pins in I/O bank 3 must operate at 2.5 V because the V_{CCIO} level of SSTL-2 is 2.5 V. I/O banks 1, 2, 3, and 4 support DQS signals with DQ bus modes of ×8.

For ×8 mode, there are up to eight groups of programmable DQS and DQ pins, I/O banks 1, 2, 3, and 4 each have two groups in the 324-pin and 400-pin FineLine BGA packages. Each group consists of one DQS pin, a set of eight DQ pins, and one DM pin (see Figure 2–33). Each DQS pin drives the set of eight DQ pins within that group.

Figure 2–33. Cyclone Device DQ and DQS Groups in ×8 Mode *Note (1)*



Note to Figure 2–33:
(1) Each DQ group consists of one DQS pin, eight DQ pins, and one DM pin.

Table 2–10 shows the number of DQ pin groups per device.

Table 2–10. DQ Pin Groups (Part 1 of 2)

Device	Package	Number of ×8 DQ Pin Groups	Total DQ Pin Count
EP1C3	100-pin TQFP *(1)*	3	24
	144-pin TQFP	4	32
EP1C4	324-pin FineLine BGA	8	64
	400-pin FineLine BGA	8	64

of the standard. Using minimum settings provides signal slew rate control to reduce system noise and signal overshoot. Table 2–11 shows the possible settings for the I/O standards with drive strength control.

Table 2–11. Programmable Drive Strength Note (1)

I/O Standard	I_{OH}/I_{OL} Current Strength Setting (mA)
LVTTL (3.3 V)	4
	8
	12
	16
	24 (2)
LVCMOS (3.3 V)	2
	4
	8
	12 (2)
LVTTL (2.5 V)	2
	8
	12
	16 (2)
LVTTL (1.8 V)	2
	8
	12 (2)
LVCMOS (1.5 V)	2
	4
	8 (2)

Notes to Table 2–11:
(1) SSTL-3 class I and II, SSTL-2 class I and II, and 3.3-V PCI I/O Standards do not support programmable drive strength.
(2) This is the default current strength setting in the Quartus II software.

Open-Drain Output

Cyclone devices provide an optional open-drain (equivalent to an open-collector) output for each I/O pin. This open-drain output enables the device to provide system-level control signals (e.g., interrupt and write-enable signals) that can be asserted by any of several devices.

Slew-Rate Control

The output buffer for each Cyclone device I/O pin has a programmable output slew-rate control that can be configured for low noise or high-speed performance. A faster slew rate provides high-speed transitions for high-performance systems. However, these fast transitions may introduce noise transients into the system. A slow slew rate reduces system noise, but adds a nominal delay to rising and falling edges. Each I/O pin has an individual slew-rate control, allowing the designer to specify the slew rate on a pin-by-pin basis. The slew-rate control affects both the rising and falling edges.

Bus Hold

Each Cyclone device I/O pin provides an optional bus-hold feature. The bus-hold circuitry can hold the signal on an I/O pin at its last-driven state. Since the bus-hold feature holds the last-driven state of the pin until the next input signal is present, an external pull-up or pull-down resistor is not necessary to hold a signal level when the bus is tri-stated.

The bus-hold circuitry also pulls undriven pins away from the input threshold voltage where noise can cause unintended high-frequency switching. The designer can select this feature individually for each I/O pin. The bus-hold output will drive no higher than V_{CCIO} to prevent overdriving signals. If the bus-hold feature is enabled, the device cannot use the programmable pull-up option. Disable the bus-hold feature when the I/O pin is configured for differential signals.

The bus-hold circuitry uses a resistor with a nominal resistance (RBH) of approximately 7 kΩ to pull the signal level to the last-driven state. Table 4–15 on page 4–6 gives the specific sustaining current for each V_{CCIO} voltage level driven through this resistor and overdrive current used to identify the next-driven input level.

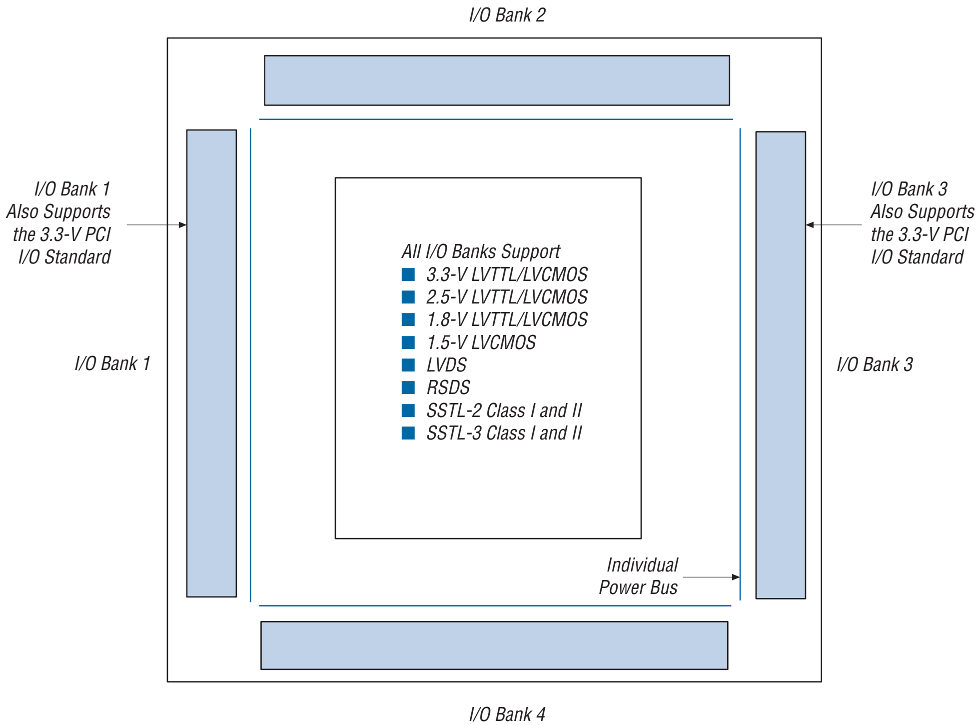
The bus-hold circuitry is only active after configuration. When going into user mode, the bus-hold circuit captures the value on the pin present at the end of configuration.

Programmable Pull-Up Resistor

Each Cyclone device I/O pin provides an optional programmable pull-up resistor during user mode. If the designer enables this feature for an I/O pin, the pull-up resistor (typically 25 kΩ) holds the output to the V_{CCIO} level of the output pin's bank. Dedicated clock pins do not have the optional programmable pull-up resistor.

and DM pins to support a DDR SDRAM or FCRAM interface. I/O bank 1 can also support a DDR SDRAM or FCRAM interface, however, the configuration input pins in I/O bank 1 must operate at 2.5 V. I/O bank 3 can also support a DDR SDRAM or FCRAM interface, however, all the JTAG pins in I/O bank 3 must operate at 2.5 V.

Figure 2–35. Cyclone I/O Banks *Notes (1), (2)*



Notes to Figure 2–35:

(1) Figure 2–35 is a top view of the silicon die.

(2) Figure 2–35 is a graphic representation only. Refer to the pin list and the Quartus II software for exact pin locations.

Each I/O bank has its own `VCCIO` pins. A single device can support 1.5-V, 1.8-V, 2.5-V, and 3.3-V interfaces; each individual bank can support a different standard with different I/O voltages. Each bank also has dual-purpose `VREF` pins to support any one of the voltage-referenced standards (e.g., SSTL-3) independently. If an I/O bank does not use voltage-referenced standards, the V_{REF} pins are available as user I/O pins.

Table 3–1. Cyclone JTAG Instructions (Part 2 of 2)

JTAG Instruction	Instruction Code	Description
USERCODE	00 0000 0111	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE to be serially shifted out of TDO.
IDCODE	00 0000 0110	Selects the IDCODE register and places it between TDI and TDO, allowing the IDCODE to be serially shifted out of TDO.
HIGHZ *(1)*	00 0000 1011	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation, while tri-stating all of the I/O pins.
CLAMP *(1)*	00 0000 1010	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation while holding I/O pins to a state defined by the data in the boundary-scan register.
ICR instructions	—	Used when configuring a Cyclone device via the JTAG port with a MasterBlaster™ or ByteBlasterMV™ download cable, or when using a Jam File or Jam Byte-Code File via an embedded processor.
PULSE_NCONFIG	00 0000 0001	Emulates pulsing the nCONFIG pin low to trigger reconfiguration even though the physical pin is unaffected.
CONFIG_IO	00 0000 1101	Allows configuration of I/O standards through the JTAG chain for JTAG testing. Can be executed before, after, or during configuration. Stops configuration if executed during configuration. Once issued, the CONFIG_IO instruction will hold nSTATUS low to reset the configuration device. nSTATUS is held low until the device is reconfigured.
SignalTap II instructions	—	Monitors internal device operation with the SignalTap II embedded logic analyzer.

Note to Table 3–1:

(1) Bus hold and weak pull-up resistor features override the high-impedance state of HIGHZ, CLAMP, and EXTEST.

In the Quartus II software, there is an Auto Usercode feature where you can choose to use the checksum value of a programming file as the JTAG user code. If selected, the checksum is automatically loaded to the USERCODE register. Choose Assignments > Device > Device and Pin Options > General. Turn on **Auto Usercode**.

Figure 3–1 shows the timing requirements for the JTAG signals.

Figure 3–1. Cyclone JTAG Waveforms

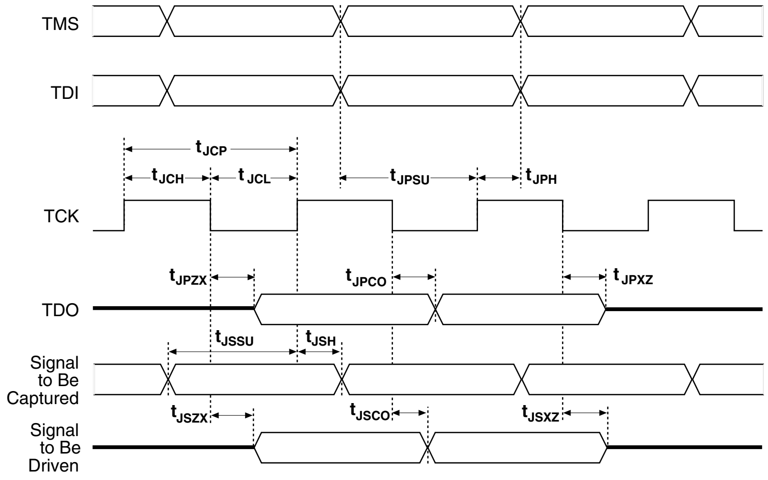


Table 3–4 shows the JTAG timing parameters and values for Cyclone devices.

Table 3–4. Cyclone JTAG Timing Parameters and Values

Symbol	Parameter	Min	Max	Unit
t_{JCP}	`TCK` clock period	100	—	ns
t_{JCH}	`TCK` clock high time	50	—	ns
t_{JCL}	`TCK` clock low time	50	—	ns
t_{JPSU}	JTAG port setup time	20	—	ns
t_{JPH}	JTAG port hold time	45	—	ns
t_{JPCO}	JTAG port clock to output	—	25	ns
t_{JPZX}	JTAG port high impedance to valid output	—	25	ns
t_{JPXZ}	JTAG port valid output to high impedance	—	25	ns
t_{JSSU}	Capture register setup time	20	—	ns
t_{JSH}	Capture register hold time	45	—	ns
t_{JSCO}	Update register clock to output	—	35	ns
t_{JSZX}	Update register high impedance to valid output	—	35	ns
t_{JSXZ}	Update register valid output to high impedance	—	35	ns

Operating Modes

The Cyclone architecture uses SRAM configuration elements that require configuration data to be loaded each time the circuit powers up. The process of physically loading the SRAM data into the device is called configuration. During initialization, which occurs immediately after configuration, the device resets registers, enables I/O pins, and begins to operate as a logic device. Together, the configuration and initialization processes are called command mode. Normal device operation is called user mode.

SRAM configuration elements allow Cyclone devices to be reconfigured in-circuit by loading new configuration data into the device. With real-time reconfiguration, the device is forced into command mode with a device pin. The configuration process loads different configuration data, reinitializes the device, and resumes user-mode operation. Designers can perform in-field upgrades by distributing new configuration files either within the system or remotely.

A built-in weak pull-up resistor pulls all user I/O pins to V_{CCIO} before and during device configuration.

The configuration pins support 1.5-V/1.8-V or 2.5-V/3.3-V I/O standards. The voltage level of the configuration output pins is determined by the V_{CCIO} of the bank where the pins reside. The bank V_{CCIO} selects whether the configuration inputs are 1.5-V, 1.8-V, 2.5-V, or 3.3-V compatible.

Configuration Schemes

Designers can load the configuration data for a Cyclone device with one of three configuration schemes (see Table 3–5), chosen on the basis of the target application. Designers can use a configuration device, intelligent controller, or the JTAG port to configure a Cyclone device. A low-cost configuration device can automatically configure a Cyclone device at system power-up.

Table 4–2. Cyclone Device Recommended Operating Conditions (Part 2 of 2)

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_O	Output voltage		0	V_{CCIO}	V
T_J	Operating junction temperature	For commercial use	0	85	° C
		For industrial use	–40	100	° C
		For extended-temperature use	–40	125	° C

Table 4–3. Cyclone Device DC Operating Conditions *Note (6)*

Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
I_I	Input pin leakage current	$V_I = V_{CCIOmax}$ to 0 V *(8)*	–10	—	10	μA
I_{OZ}	Tri-stated I/O pin leakage current	$V_O = V_{CCIOmax}$ to 0 V *(8)*	–10	—	10	μA
I_{CC0}	V_{CC} supply current (standby) (All M4K blocks in power-down mode) *(7)*	EP1C3	—	4	—	mA
		EP1C4	—	6	—	mA
		EP1C6	—	6	—	mA
		EP1C12	—	8	—	mA
		EP1C20	—	12	—	mA
R_{CONF} *(9)*	Value of I/O pin pull-up resistor before and during configuration	$V_I = 0$ V; $V_{CCIO} = 3.3$ V	15	25	50	kΩ
		$V_I = 0$ V; $V_{CCIO} = 2.5$ V	20	45	70	kΩ
		$V_I = 0$ V; $V_{CCIO} = 1.8$ V	30	65	100	kΩ
		$V_I = 0$ V; $V_{CCIO} = 1.5$ V	50	100	150	kΩ
	Recommended value of I/O pin external pull-down resistor before and during configuration	—	—	1	2	kΩ

Table 4–4. LVTTL Specifications

Symbol	Parameter	Conditions	Minimum	Maximum	Unit
V_{CCIO}	Output supply voltage	—	3.0	3.6	V
V_{IH}	High-level input voltage	—	1.7	4.1	V
V_{IL}	Low-level input voltage	—	–0.5	0.7	V
V_{OH}	High-level output voltage	$I_{OH} = –4$ to $–24$ mA *(11)*	2.4	—	V
V_{OL}	Low-level output voltage	$I_{OL} = 4$ to 24 mA *(11)*	—	0.45	V

Table 4–10. 3.3-V PCI Specifications (Part 2 of 2)						
Symbol	**Parameter**	**Conditions**	**Minimum**	**Typical**	**Maximum**	**Unit**
V_{OH}	High-level output voltage	I_{OUT} = –500 µA	0.9 × V_{CCIO}	—	—	V
V_{OL}	Low-level output voltage	I_{OUT} = 1,500 µA	—	—	0.1 × V_{CCIO}	V

Table 4–11. SSTL-2 Class I Specifications						
Symbol	**Parameter**	**Conditions**	**Minimum**	**Typical**	**Maximum**	**Unit**
V_{CCIO}	Output supply voltage	—	2.375	2.5	2.625	V
V_{TT}	Termination voltage	—	V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04	V
V_{REF}	Reference voltage	—	1.15	1.25	1.35	V
V_{IH}	High-level input voltage	—	V_{REF} + 0.18	—	3.0	V
V_{IL}	Low-level input voltage	—	–0.3	—	V_{REF} – 0.18	V
V_{OH}	High-level output voltage	I_{OH} = –8.1 mA *(11)*	V_{TT} + 0.57	—	—	V
V_{OL}	Low-level output voltage	I_{OL} = 8.1 mA *(11)*	—	—	V_{TT} – 0.57	V

Table 4–12. SSTL-2 Class II Specifications						
Symbol	**Parameter**	**Conditions**	**Minimum**	**Typical**	**Maximum**	**Unit**
V_{CCIO}	Output supply voltage	—	2.3	2.5	2.7	V
V_{TT}	Termination voltage	—	V_{REF} – 0.04	V_{REF}	V_{REF} + 0.04	V
V_{REF}	Reference voltage	—	1.15	1.25	1.35	V
V_{IH}	High-level input voltage	—	V_{REF} + 0.18	—	V_{CCIO} + 0.3	V
V_{IL}	Low-level input voltage	—	–0.3	—	V_{REF} – 0.18	V
V_{OH}	High-level output voltage	I_{OH} = –16.4 mA *(11)*	V_{TT} + 0.76	—	—	V
V_{OL}	Low-level output voltage	I_{OL} = 16.4 mA *(11)*	—	—	V_{TT} – 0.76	V

Table 4–13. SSTL-3 Class I Specifications (Part 1 of 2)						
Symbol	**Parameter**	**Conditions**	**Minimum**	**Typical**	**Maximum**	**Unit**
V_{CCIO}	Output supply voltage	—	3.0	3.3	3.6	V
V_{TT}	Termination voltage	—	V_{REF} – 0.05	V_{REF}	V_{REF} + 0.05	V

Table 4–16. Cyclone Device Capacitance *Note (14)*			
Symbol	**Parameter**	**Typical**	**Unit**
C_{IO}	Input capacitance for user I/O pin	4.0	pF
C_{LVDS}	Input capacitance for dual-purpose LVDS/user I/O pin	4.7	pF
C_{VREF}	Input capacitance for dual-purpose V_{REF}/user I/O pin.	12.0	pF
C_{DPCLK}	Input capacitance for dual-purpose `DPCLK`/user I/O pin.	4.4	pF
C_{CLK}	Input capacitance for CLK pin.	4.7	pF

Notes to Tables 4–1 through 4–16:

(1) Refer to the *Operating Requirements for Altera Devices Data Sheet*.

(2) Conditions beyond those listed in Table 4–1 may cause permanent damage to a device. Additionally, device operation at the absolute maximum ratings for extended periods of time may have adverse affects on the device.

(3) Minimum DC input is –0.5 V. During transitions, the inputs may undershoot to –2.0 V or overshoot to 4.6 V for input currents less than 100 mA and periods shorter than 20 ns.

(4) Maximum V_{CC} rise time is 100 ms, and V_{CC} must rise monotonically.

(5) All pins, including dedicated inputs, clock, I/O, and JTAG pins, may be driven before V_{CCINT} and V_{CCIO} are powered.

(6) Typical values are for T_A = 25° C, V_{CCINT} = 1.5 V, and V_{CCIO} = 1.5 V, 1.8 V, 2.5 V, and 3.3 V.

(7) V_I = ground, no load, no toggling inputs.

(8) This value is specified for normal device operation. The value may vary during power-up. This applies for all V_{CCIO} settings (3.3, 2.5, 1.8, and 1.5 V).

(9) R_{CONF} is the measured value of internal pull-up resistance when the I/O pin is tied directly to GND. R_{CONF} value will be lower if an external source drives the pin higher than V_{CCIO}.

(10) Pin pull-up resistance values will lower if an external source drives the pin higher than V_{CCIO}.

(11) Drive strength is programmable according to values in *Cyclone Architecture* chapter in the *Cyclone Device Handbook*.

(12) Overdrive is possible when a 1.5 V or 1.8 V and a 2.5 V or 3.3 V input signal feeds an input pin. Turn on “Allow voltage overdrive” for LVTTL/LVCMOS input pins in the Assignments > Device > Device and Pin Options > Pin Placement tab when a device has this I/O combination. However, higher leakage current is expected.

(13) The Cyclone LVDS interface requires a resistor network outside of the transmitter channels.

(14) Capacitance is sample-tested only. Capacitance is measured using time-domain reflections (TDR). Measurement accuracy is within ±0.5 pF.

Table 4–49. Cyclone Maximum Input Clock Rate for Row Pins				
I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit
LVTTL	464	428	387	MHz
2.5 V	392	302	207	MHz
1.8 V	387	311	252	MHz
1.5 V	387	320	243	MHz
LVCMOS	405	374	333	MHz
SSTL-3 class I	405	356	293	MHz
SSTL-3 class II	414	365	302	MHz
SSTL-2 class I	464	428	396	MHz
SSTL-2 class II	473	432	396	MHz
3.3-V PCI *(1)*	464	428	387	MHz
LVDS	567	549	531	MHz

Note to Tables 4–48 through 4–49:
(1) EP1C3 devices do not support the PCI I/O standard. These parameters are only available on row I/O pins.

Tables 4–50 and 4–51 show the maximum output clock rate for column and row pins in Cyclone devices.

Table 4–50. Cyclone Maximum Output Clock Rate for Column Pins				
I/O Standard	-6 Speed Grade	-7 Speed Grade	-8 Speed Grade	Unit
LVTTL	304	304	304	MHz
2.5 V	220	220	220	MHz
1.8 V	213	213	213	MHz
1.5 V	166	166	166	MHz
LVCMOS	304	304	304	MHz
SSTL-3 class I	100	100	100	MHz
SSTL-3 class II	100	100	100	MHz
SSTL-2 class I	134	134	134	MHz
SSTL-2 class II	134	134	134	MHz
LVDS	320	320	275	MHz

Note to Table 4–50:
(1) EP1C3 devices do not support the PCI I/O standard.

Referenced Document

This chapter references the following documents:

- *Cyclone Architecture* chapter in the *Cyclone Device Handbook*
- *Operating Requirements for Altera Devices Data Sheet*

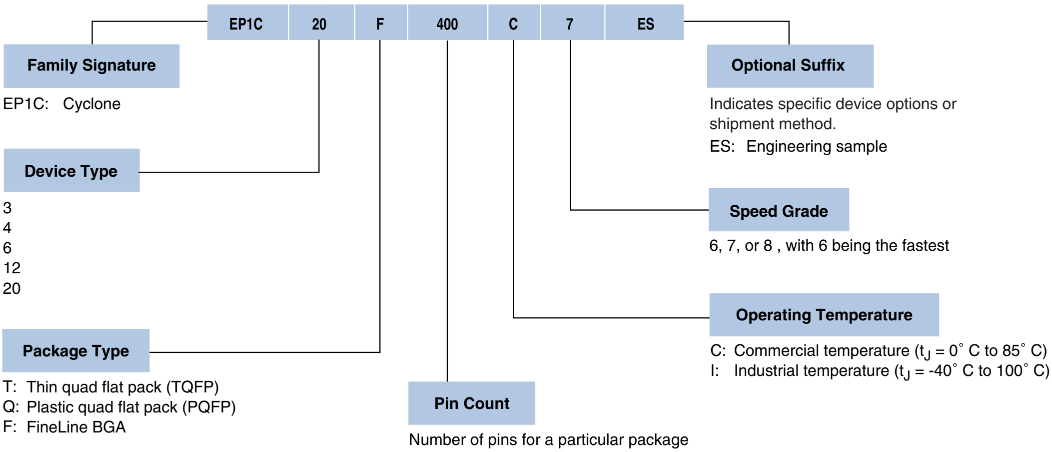
Document Revision History

Table 4–53 shows the revision history for this chapter.

Table 4–53. Document Revision History

Date and Document Version	Changes Made	Summary of Changes
May 2008 v1.7	Minor textual and style changes. Added "Referenced Document" section.	—
January 2007 v1.6	• Added document revision history. • Added new row for V_{CCA} details in Table 4–1. • Updated R_{CONF} information in Table 4–3. • Added new *Note (12)* on voltage overdrive information to Table 4–7 and Table 4–8. • Updated *Note (9)* on R_{CONF} information to Table 4–3. • Updated information in "External I/O Delay Parameters" section. • Updated speed grade information in Table 4–46 and Table 4–47. • Updated LVDS information in Table 4–51.	—
August 2005 v1.5	Minor updates.	—
February 2005 v1.4	• Updated information on Undershoot voltage. Updated Table 4-2. • Updated Table 4-3. • Updated the undershoot voltage from 0.5 V to 2.0 V in Note 3 of Table 4-16. • Updated Table 4-17.	—
January 2004 v.1.3	• Added extended-temperature grade device information. Updated Table 4-2. • Updated I_{CC0} information in Table 4-3.	—
October 2003 v.1.2	• Added clock tree information in Table 4-19. • Finalized timing information for EP1C3 and EP1C12 devices. Updated timing information in Tables 4-25 through 4-26 and Tables 4-30 through 4-51. • Updated PLL specifications in Table 4-52.	—

Figure 5–1. Cyclone Device Packaging Ordering Information



Referenced Documents

This chapter references the following documents:

- *Package Information for Cyclone Devices* chapter in the *Cyclone Device Handbook*
- *Quartus II Handbook*

Document Revision History

Table 5–1 shows the revision history for this chapter.

Table 5–1. Document Revision History

Date and Document Version	Changes Made	Summary of Changes
May 2008 v1.4	Minor textual and style changes. Added "Referenced Documents" section.	—
January 2007 v1.3	Added document revision history.	—
August 2005 v1.2	Minor updates.	—